**Supporting Information** 

## Laser power and high-temperature dependent Raman study of layered bismuth and copper-based oxytellurides for optoelectronic applications

Prabhukrupa C. Kumar<sup>1</sup>, Subrata Senapati<sup>1\*</sup>, Monalisa Pradhan<sup>2</sup>, Gopal K. Pradhan<sup>2</sup>, Ramakanta Naik<sup>1\*</sup>

<sup>1</sup> Department of Engineering and Materials Physics, Institute of Chemical Technology-Indian Oil Odisha Campus, Bhubaneswar, 751013, India

<sup>2</sup> Department of Physics, School of Applied Science, KIIT Deemed to be University, Bhubaneswar, 751024, India

\*Email: <u>subrata.uu@gmail.com</u>

ramakanta.naik@gmail.com



Fig. S1 XRD pattern with the respective matched ICSD cards for (a) BiCuOTe, (b)  $Bi_2O_5Te$  and (c)  $Cu_2O_8Te_3$  samples.



**Fig. S2** (a) Combined elemental mapping of the Bi<sub>2</sub>O<sub>5</sub>Te nanosheets and (b-d) elemental mapping of the individual Bi, O, and Te elements.



**Fig. S3** (a) Combined elemental mapping of the  $Cu_2O_8T_3$  NS and (b-d) elemental mapping of the individual Cu, Te, and O elements.



Fig. S4 Particle size distribution histogram of (a) BiCuOTe, (b)  $Bi_2O_5Te$ , and (c)  $Cu_2O_8Te_3$  samples.



Fig. S5 Diffuse reflectance spectra of (a) BiCuOTe, (b) Bi<sub>2</sub>O<sub>5</sub>Te, and (c) Cu<sub>2</sub>O<sub>8</sub>Te<sub>3</sub> powder sample.

Table S1 Structural parameters obtained from XRD peak analysis.

| Samples  | Average Crystallite Size<br>(D) (nm) | Dislocation density(δ)<br>(nm <sup>2</sup> ) | Lattice Strain (ɛ) |
|--|--------------------------------------|--|--------------------|
| BiCuOTe  | 20.36                                | 0.00347                                      | 0.00539            |
| Bi <sub>2</sub> O <sub>5</sub> Te              | 20.18                                | 0.00537                                      | 0.00539            |
| Cu <sub>2</sub> O <sub>8</sub> Te <sub>3</sub> | 13.98                                | 0.00560                                      | 0.00735            |



**Fig. S6** Atomic configuration of BiCuOTe tetragonal crystal lattice system (a) side view and (b) top view with P4/nmm space group where the solid-line box shows the unit cell.<sup>1</sup>



Fig. S7 Atomic configuration of  $Bi_2O_5Te$  orthorhombic lattice phase (a) side view and (b) top view with Aem2 space group where the unit cell is represented in solid-line box.<sup>2</sup>



Fig. S8 Atomic configuration of  $Cu_2O_8Te_3$  monoclinic crystal lattice system (a) side view and (b) top view with C2/c space group where the unit cell is exhibited by solid-line box.<sup>3</sup>



**Fig. S9** Comparative plot between (a) FWHM of Raman peaks with respect to temperature, (b) Raman shift against temperature for Raman peaks appeared within 90~96 cm<sup>-1</sup> and (c) statistical representation of the variation in Raman shift and FWHM of Raman peaks of each sample.



**Fig. S10** Comparative plot between (a) Raman shift against laser power for Raman peaks that appeared within 145~164 cm<sup>-1</sup> and (b) statistical representation of the variation in Raman shift of each sample.

## Notes and references

1 Data retrieved from the Materials Project for CuBiTeO (mp-545369) from database version v2023.11.1.

2 Data retrieved from the Materials Project for  $Bi_2TeO_5$  (mp-23334) from database version v2023.11.1.

3 Data retrieved from the Materials Project for  $Cu_2Te_3O_8$  (mp-17598) from database version v2023.11.1.